

Notice of References Cited	Application/Control No. 10/563,650	Applicant(s)/Patent Under Reexamination DOOLEY ET AL.	
	Examiner Almis R. Jankus	Art Unit 2628	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0266457	12-2004	Dupray, Dennis J.	455/456.5
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Yost et al., "Comments on Circular vs. Elliptical Errors in Automatic Location Identification"; IEEE, 1998, pages 673-678.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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